# Low Power 4 Bit Flash Adc Using Multiple Selection Method In 45nm 

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Article Info<br>Volume 82<br>Page Number: 3214-3223<br>Publication Issue:<br>January-February 2020

## Article History

Article Received: 14 March 2019
Revised: 27 May 2019
Accepted: 16 October 2019
Publication: 19 January 2020


#### Abstract

Simple to-Digital Converters (ADCs) are helpful structure obstructs in numerous applications, for example, information stockpiling read channel and an optical beneficiary since they speak to the interface between this present reality simple sign and the advanced sign processors. Numerous executions have been accounted for in the writing so as to get rapid ADCs. In this undertaking an exertion is made to plan 4-piece Flash ADC utilizing 180 nm and 45 nm CMOS innovation. ADCs are fundamental to numerous cutting edge frameworks that require the mix of simple sign with advanced frameworks. The uses of advanced framework can extend from sound to interchanges applications to therapeutic applications. These converters are executed utilizing an assortment of designs, sizes and speed. The interest for the converter is situated on zone, speed and intensity of the converters. The coordinated blaze ADC is worked at 4-piece exactness. Streak ADC is investigated, planned and thought about in standard gpdk180nm and 45 nm innovation utilizing rhythm apparatuses.


Keywords: Digital Converters, interchanges applications

## I. INTRODUCTION

With the fast development of current interchanges and sign preparing frameworks, handheld remote PCs and shopper hardware are winding up progressively prominent. Blended sign coordinated circuits have an inclination in the plan of framework on chip (SoC) as of late. SoC plans have made conceivable significant expense and structure factor decreases, to some extent since they coordinate essential simple interface circuits, for example, simple to advanced converters with computerized registering and sign handling circuits on a similar kick the bucket.

The interfaces just involve a little part of the chip kick the bucket and for SOC structures, the innovation choice and framework plan decisions are for the most part determined by advanced circuit necessities. ADCs are fundamental to numerous cutting edge frameworks that require the reconciliation of simple sign with computerized
frameworks. The utilizations of advanced framework can run from sound to interchanges applications to medicinal Applications. These converters are actualized utilizing an assortment of structures, sizes and speeds. The interest for the converter is located on territory, velocity, depth of the converters.

For fast programs, a glimmer ADC is often carried out. Goals, tempo, and electricity usage are the three key parameters for an ADC. These parameters cannot be changed once an ADC is deliberate. While you may employ 6-piece accuracy from a eightpiece ADC, it's far non-satisfactory coming about in extra sluggish speed and extra power utilization because of full eight-piece inner interest. Most modern advanced frameworks include of diverse integrated circuits (ICs), which want to talk with every other. As the preparing pace of each IC builds, it requests more and more extended information/yield (I/O) data switch capability. The
term fast connection alludes to each the physical channel and the I/O circuits whose objective is to assist this growing requirement for statistics transmission. To maintain up, speedy connections are forced to utilize gradually parallel channels and increment the facts rate in each channel.

Simple to advanced converters are the vital structure obstructs that deliver an interface amongst a easy world and the automated place. As it's miles the precept ward off in blended signal programs, it turns into a bottleneck trouble in data handling applications and boundaries the exhibition of the general framework. In this the presentation of quantity of $A / D$ converter designs are mentioned. From the important that means of ADC excellent engineering of ADCs that incorporate Flash, Successive Approximation (SAR), Sigma-Delta, Pipeline and Dual Slope ADCs are mentioned. At final, the specific present ADC designs are notion about and the following territory productiveness of the equivalent is portrayed.

Simple to Digital Converter (ADC) is a gadget that recognizes a easy really worth (voltage/modernday) and adjustments over it into advanced shape that may be prepared by using manner of a microchip.


Figure 1. Block Diagram of ADC

## Ordinary FLASH ADC

Streak ADC's are likewise referred to as parallel ADCs. Because of the parallel format it's miles the fastest

ADC some of the various kinds and are suitable for excessive transmission potential programs. Because of essence of 2 n resistor it expends a ton of depth, has low dreams, and high priced for immoderate goals. It is for the most part utilized in excessive recurrence programs and in different styles of ADC fashions. Scarcely any utilizations of blaze ADCs are satellite tv for pc correspondence, radar making prepared, data procurement, checking
out oscilloscopes, and high-thickness circle drives. A run of the mill streak ADC square chart is appeared in figure.2:


Figure2 Block Diagram of Flash Type ADC
It very well may Be seen from the square graph that $2 \mathrm{n}-1$ comparators are required for a " N " bit converter. The resistor stepping stool device is shaped thru 2 n resistors, it is carried out to creates the +reference voltages for the each comparators. The reference voltage for each comparator is 1 least important piece (LSB) no longer exactly the reference voltage for the comparator immediately above it.Traditional streak ADC design uses 2 Nresistors and $2 \mathrm{~N}-1$ comparator. All comparators will work in parallel, so that it will cause excessive manipulate usage. The segment test of a blaze ADC develops exponentially with dreams. Along these lines, the region and energy wolfed by manner of the ADC circuit increment exponentially with goals.

## 4 FLASH ADC USING MULTIPLE SELECTION METHOD

The four piece streak ADC utilizing multiplexer comprises of one mux $2: 1$, three mux $4: 1$, six comparators and rationale hardware.

The great inconvenience of the conventional glimmer ADC is its excessive chip place, excessive manipulate usage and immoderate input capacitance. By and massive, this form of layout makes use of $2(\mathrm{~N}-2)+2$ comparators in preference to $2 \mathrm{~N}-1$ comparators which might be extremely much less in variety, but overhead of purpose hardware. The engineering of the planned ADC is appeared in fig 3


Figure 3 Block Diagram of 4 Bit Flash ADC Using Multiple Selection Method

### 3.5 COMPONENTS OF FLASH ADC USING MULTIPLE SELECTION METHOD

Fundamental parts of this ADC comprise

- Resistor stepping stool
- Sample and Hold circuit
- Comparator
- Multiplexer 4:1
- Multiplexer 2:1 •Logic hardware.


### 3.5.1 RESISTOR LADDER BLOCK

Instantly Analog-to-Digital Converter, resistor stepping stool square is applied to create the reference voltages for the comparators. The rectangular chart of resistor stepping stool is appeared in figure4.

In a 'n' bit streak ADC, 2 n protections are vital. The two splendid resistors are decided to delimit the voltage facts boom. Every resistor separates the reference voltage to nourish a comparator. The higher the opposition well worth is, the more fragile the modern is expended within the device. That is the cause a excessive obstruction will restriction manipulate dispersal. By and with the aid of the use of, we need to position a sensible incentive for this resistor string it must stand lower than the statistics obstruction of the comparators. Since every one of
the protections are of equivalent worth, the voltage levels accessible at the hubs are similarly partitioned between the reference voltage Vr and the ground.


Figure 4. Resistor Ladder
Figure 5 shows transient response of resistor string:


Figure 5 Transient Response of Resistor String

Advantage: Higher impedance values can be reached using the same number of components Figure 3.15 shows resistor ladder schematic:

### 3.5.2 SAMPLE AND HOLD BLOCK

Test and Hold circuit arrangement is furthermore a basic structure which is used as a piece of the AMS based plans. The Sample and Hold utilizes a capacitor and a simple change to interface or separate the capacitor from the information. In examining mode the switch is
"on", making the sign way that enables the capacitor to follow an information voltage. At the point when the switch is "off" an open circuit is made that separates the capacitor from the information, subsequently changing the circuit from examining mode in to holding mode.

The Figure 6 demonstrates the CMOS schematic level outline of test and hold circuit. The voltage supporter circuit offers solidarity gain with the high impedance to info sign and low impedance.


Figure 6. Schematic of Sample and Hold Circuit


Figure 4.12 Transient Response of Sample and Hold

### 3.5.3 COMPARATOR BLOCK

A comparator is utilized to identify whether a sign is more prominent or littler than reference signal. Comparators are generally utilized in A/D converter structure.

Square outline of comparator utilized in planned ADC is appeared in Figure 7 as the CMOS innovation devours less control so comparator utilized in glimmer ADC is structured utilizing

CMOS innovation with the goal that it expends least control..


Figure 7. Comparator Symbol
Comparator devours noteworthy power in ADC circuits yet assumes exceptionally basic job in the planning. The parameters, for example, spread
postponement, control utilization, input balance voltage, and info scope of comparator chooses the significant parameters of glimmer ADC.

The quantity of comparator increments as the quantity of bits builds, an outcome the power
devoured and territory likewise increments exponentially. The clamor created at high frequencies in the comparator is significant. Figure 3.18 demonstrates the comparator schematic:


Figure 8. Comparator Schematic

### 4.2.1 COMPARATOR TRANSIENT RESPONSE

Figure 16 shows transient response of comparator


Figure 16. Transient Response of Comparator

### 3.5.4 Multiplexer 2X1

CMOS transmission entryways give an effective method to manufacture directing rationale. Controlling rationale circuits will be circuits that course information contributions to yields dependent on the settings of control signals. Transmission doors usage is appeared in Figure 9


Figure 9. Mux 2:1 Using Transmission Gate

The schematic of mux $2: 1$ is shown in Figure 10:


Figure 10. Schematic of Mux 2:1

The essential favorable function of utilizing transmission entryway in Mux execution is that the amount of the transistor applied has decreased basically. This has been visible that the amount of
transistor is decreased thru three.Three events as evaluation with umber of transistor in mux 2:1 dependent with rationale doors. Figure 11 shows transient reaction of multiplexer $2 \times 1$


Figure 11. Transient Response of Multiplexer 2x1

### 3.5.5 Multiplexer 4X1

Mux 4:1 has been implemented using transmission gates. It has been implemented using mux $2: 1$ as show in the Figure 3.21 and Figure 12.


Figure 12. Symbol Schematic of Mux 4:1


Figure 13. Mux 4:1 Using Transmission Gate
This has been observed that the quantity of transistor applied in mux four:1 using transmission gates are $35 \%$ plenty less than the mux 4:1 designed with good judgment gates.
4.4.1 MULTIPLEXER 4X1 TRANSIENT RESPONSE

Figure 13 indicates brief response of multiplexer 4x1


Figure 13 Transient Response of Multiplexer $4 \times 1$

The good judgment circuitry used inside the structure of the proposed ADC implement the following fact table to generate the B 0 little little bit of the binary output as proven in Table 1

Table1 Truth Table Of Logic Circuit

| c4 | c5 | c6 | B1 | B0 |
| :---: | :---: | :---: | :---: | :---: |
| 0 | 0 | 0 | 0 | 0 |
| 1 | 0 | 0 | 1 | 0 |
| 1 | 1 | 0 | 0 | 1 |
| 1 | 1 | 1 | 1 | 1 |

$$
\mathrm{B} 1=\mathrm{C} 4 \overline{\mathrm{C} 5}+\mathrm{C} 6 \quad \mathrm{BO}=\overline{\overline{\mathrm{C4}}}=\mathrm{C} 4
$$

Logic circuitry used to generate the B0 bit of the binary output with $\mathrm{C} 4, \mathrm{C} 5$ and C 6 as inputs are shown in the Figure 14:

### 3.5.6 Logic circuitry



Figure 14. Schematic of Logic Circuit


Figure 4.10 Transient Response of Logic Circuit

Simple information Given to the ADC thru example and maintain circuit. This statistics goes
to the non-enhancing contribution of comparator $\mathrm{C} 1, \mathrm{C} 2$ and C 3 and rearranging statistics assets are
related to $8 \mathrm{Vref} / 16,4 \mathrm{Vref} / 16$, and $12 \mathrm{Vref} / 16$ one at a time to create the MSBs. The yields of comparators are applied to manipulate the yield of Multiplexer $2: 1$. Hence, B3 and B2 are selected via the yields of comparators $\mathrm{C} 1, \mathrm{C} 2, \mathrm{C} 3$ and Multiplexer $2: 1$. The yields B3 and B2 are related to pick line of each one of the Multiplexer four:1, this turns on appropriate Vref on the contribution of comparator $\mathrm{C} 4, \mathrm{C} 5$ and C 6 . The yields of the comparator $\mathrm{C} 4, \mathrm{C} 5$ and C 6 pick out out the yield twofold bits B1 and B0. The plan of the glimmer ADC utilizes six comparators and some extra overhead of multiplexers instead of fifteen comparator, sixteen EXOR doors and encoder of conventional blaze ADC. In this manner, it diminishes territory and electricity expended.
3.6 PRINCIPLE OF OPERATION OF FLASH ADC
$\square \quad$ Analog info given to the ADC through example and hold circuit.
$\square \quad$ This info goes to the non-modifying contribution of comparator $\mathrm{C} 1, \mathrm{C} 2$ and C 3
$\square \quad$ Inverting data sources are associated with $8 \mathrm{Vref} / 16,4 \mathrm{Vref} / 16$, and $12 \mathrm{Vref} / 16$ separately to create the MSBs.

The yields of comparators are utilized to control the yield of Multiplexer $2: 1$.
$\square \quad$ Thus, B3 and B2 are chosen by the yields of comparators $\mathrm{C} 1, \mathrm{C} 2, \mathrm{C} 3$ and Multiplexer $2: 1$

The yields B3 and B2 are associated with select line of every one of the Multiplexer $4: 1$, this
prompts fitting Vref at the contribution of comparator $\mathrm{C} 4, \mathrm{C} 5$ and C 6.
$\square \quad$ The yields of the comparator C4, C5 and C6 choose the yield double bits B1 and B0

## IV. RESULTS

### 4.1 RESISTOR STRING TEST CIRCUIT

In the below response the voltage divider divides the output by

Reference voltage *no. of bit/ number of inputs
$=1.8 * 1 / 16=0.1125 \mathrm{~V}$
$=1.8 * 2 / 16=0.225 \mathrm{~V}$
$=1.8 * 3 / 16=0.3375 \mathrm{~V}$
$=1.8 * 4 / 16=0.5625 \mathrm{~V}$
$=1.8 * 5 / 16=0.6750 \mathrm{~V}$
$=1.8 * 6 / 16=0.7875 \mathrm{~V}$
$=1.8 * 7 / 16=0.9000 \mathrm{~V}$
$=1.8 * 8 / 16=1.0125 \mathrm{~V}$
$=1.8 * 9 / 16=1.1250 \mathrm{~V}$
$=1.8 * 10 / 16=1.2375 \mathrm{~V}$
$=1.8 * 11 / 16=1.35 \mathrm{~V}$
$=1.8 * 12 / 16=1.4625 \mathrm{~V}$
$=1.8 * 13 / 16=1.575 . \mathrm{V}$
$=1.8 * 14 / 16=1.6875 \mathrm{~V}$
$=1.8 * 15 / 16=1.8 \mathrm{~V}$

### 4.7 4-BIT FLASH ADC

Figure 4.13 shows test circuit of 4 bit flash ADC


Figure 4.13 Test Circuit of 4 bit Flash ADC
4.7.1 4-BIT FLASH ADC TRANSIENT RESPONSE IN 180 nm

Figure 4.14 shows transient response 4 bit Flash ADC in 180nm


Figure 4.14 Transient Response 4 Bit Flash ADC in 180nm

### 4.7.2 4-BIT FLASH ADC TRANSIENT RESPONSE IN 45 nm

Figure 4.15 shows transient response of 4 bit Flash ADC in 45 nm .


Figure 4.15 Transient Response of 4 bit Flash ADC In 45nm

### 4.7.3 Digital output with respect to analog input

Table 4.1 Digital output with respect to analog input 4.8 COMPARISION OF SPECIFICATIONS OF 4-BIT FLASH ADC IN 180 nm and 45 nm TECHNOLOGY

| Analog input Va | B[3] | B[2] | B[1] | B[0] |
| :---: | :---: | :---: | :---: | :---: |
| $0<=\mathrm{Va} \leqslant \mathrm{V} 1$ | 0 | 0 | 0 | 0 |
| $\mathrm{V} 1<=\mathrm{Va} \leqslant \mathrm{V} 2$ | 0 | 0 | 0 | 1 |
| V2 $=$ VacV3 | 0 | 0 | 1 | 0 |
| V3 $<=\mathrm{Va} \leqslant \mathrm{V} 4$ | 0 | 0 | 1 | 1 |
| V4 $¢=\mathrm{Va}<\mathrm{V} 5$ | 0 | 1 | 0 | 0 |
| V5 $=$ VacV6 | 0 | 1 | 0 | 1 |
| V6 $<=\mathrm{Va}<\mathrm{V} 7$ | 0 | 1 | 1 | 0 |
| V7 $¢=\mathrm{Va}<\mathrm{V} 8$ | 0 | 1 | 1 | 1 |
| V8 $6=\mathrm{Va}<\mathrm{V} 9$ | 1 | 0 | 0 | 0 |
| $\mathrm{V} 9<=\mathrm{Va}<\mathrm{V} 10$ | 1 | 0 | 0 | 1 |
| $\mathrm{V} 10<=\mathrm{Va}<\mathrm{V} 11$ | 1 | 0 | 1 | 0 |
| V11 $<=\mathrm{Va}<\mathrm{V} 12$ | 1 | 0 | 1 | 1 |
| $\mathrm{V} 12 \mathrm{c}=\mathrm{Va}<\mathrm{V} 13$ | 1 | 1 | 0 | 0 |
| $\mathrm{V} 13<=\mathrm{Va}<\mathrm{V} 14$ | 1 | 1 | 0 | 1 |
| V14 $=$ Va $<$ V15 | 1 | 1 | 1 | 0 |
| $\mathrm{V} 15<=\mathrm{Va}<2.4$ | 1 | 1 | 1 | 1 |

Table 4.2 Comparison of specifications of 4 bit Flash ADC In 180nm And 45 nm Technology

| Power consumed and area |  |  |
| :--- | :--- | :--- |
| Arch. |  | Multiple selection flash <br> ADC(Designed) |
| Technology | GPDK 180nm | 45 nm |
| Resolution | 4 bit | 4 bit |
| Input Analog <br> Range | $0 \sim 2.4 \mathrm{~V}$ | $0 \sim 2.4 \mathrm{~V}$ |
| Power Consumed | 22.389 mW | 8.19 mW |
| Area (in terms of <br> transistor count) | 135 | 135 |

## V. CONCLUSION

The flash ADC is designed and implemented in standard GPDK 180 nm and 45 nm technology. The number of transistors used in flash ADC designed with multiplexer is 135 and power consumed in 180 nm technology is 22.389 mW \& 45 nm technology is 8.19 mw respectively. Thus designed flash ADC is area and power efficient..

## VI. REFERENCES

[1] D.Lee, J.Yoo, K.Choi and J. Ghaznavi, "Fattree encoder design for ultrahigh speed flash analog to digital converters" I proc. IEEE

Midwest Symp. Circuits Syst, pp 233-236, Aug 2002.
[2] Chung-Hsun Huang, Jinn-Shyan Wang, "High-performance and power-efficient CMOS comparators", IEEE Journal of SolidState Circuits, vol. 38, no. 2, pp. $254-262$, Feb. 2003.
[3] VinayashreeHiremath, SaiyuRen "An Ultra High Speed Encoder for 5GSPS Flash ADC ", IEEE Conference on Instrumentation and Measurement Technology, pp 136-141, May 2010.
[4] S. Sheikhaei, S. Mirabbasi, A. Ivanov, "An Encoder for a $5 \mathrm{GS} / \mathrm{s} 4 \mathrm{bit}$ flash A/D converter in 0.18 um CMOS", Canadian Conference on Electrical and Computer Engineering, pp 698701, May 2005.
[5] Nikoozadeh, A., Murmann, B., "An Analysis of Latch Comparator Offset Due to Load Capacitor Mismatch", IEEE Transactions on Circuits and Systems II, Vol. 53 , no. 12, Dec. 2006.
[6] Sunghyun Park, YorgosPalaskas, Ashoke Ravi, Ralph.E.Bishop, and Michael P. Flynn, " A 3.5 GS/s 5-b Flash ADC in 90 nm CMOS ", IEEE Custom Integrated Circuits Conference 2006.
[7] JayantaChoudhury, G.H. Massiha, " Efficient Encoding Sheme for Ultra-Fast Flash ADC", Topical Meeting on Silicon Monolithic Integrated Circuits in RF Systems, pp 290293, Sep 2004.
[8] Kim, J.-I., Sung, B.-R.-S., Kim, W., Ryu, S.T., "A 6-b 4.1-GS/s Flash ADC With TimeDomain Latch Interpolation in $90-\mathrm{nm}$ CMOS", IEEE Journal of Solid- State Circuits, vol. 48, no. 6, pp. 1429 - 1441, Jun. 2013.

